AMSTER ROTHSTEIN & EBENSTEIN LLP

Intellectual Property Law



David L. Hecht

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PRACTICE AREAS

- · Alternative Dispute
- Copyright
- Intellectual Property Litigation
- International Trade Commission
- Patent
- · Strategic Counseling
- Trade Dress
- Trademark

INDUSTRIES

- Computer Hardware and Software
- Consumer Electronics
- Internet and e-Commerce
- Motors, Machinery & Other Mechanical Devices
- Mobile Devices & Wireless

David L. Hecht has experience handling a broad range of intellectual property rights matters, including litigation, licensing, opinions, and prosecution. He has focused on patent issues in diverse technology areas, such as digital electronics, digital signal processing, medical devices, television receivers, telecommunication networks, and e-commerce.

Mr. Hecht received his law degree from Fordham University School of Law and his undergraduate degree in electrical and computer engineering from Rutgers University. Prior to law school, he worked as a network administrator and was involved in the design of a redundant network infrastructure for Edifice Information Management Systems. Mr. Hecht also worked at Computer Sciences Corporation (CSC), where he developed military simulator software.

Mr. Hecht is a member of the Eta Kappa Nu honor society and the Institute of Electrical and Electronics Engineers (IEEE). He has also consulted for Practicing Law Institute (PLI) and has written questions and answers for the PLI Patent Bar Review course.

He is admitted to practice in New York and New Jersey and is registered to practice before the U.S. Patent and Trademark Office.

BAR ADMISSIONS

- New York
- New Jersey
- · U.S. Patent and Trademark Office

EDUCATION

- Fordham University, New York, New York, J.D., Managing Editor, Fordham Intellectual Property, Media & Entertainment Law Journal. Moot Court Board
- Rutgers University, New Brunswick, New Jersey, M.B.A., Magna Cum Laude
- Rutgers University, New Brunswick, New Jersey, B.S., Electrical and Computer Engineering, Cum Laude

PROFESSIONAL EXPERIENCE

- · Jones Day, Associate
- · J. Schwartz & Associates, Patent Agent
- · Edifice Information Management